

**Notice of References Cited**

Application/Control No.

10/511,785

Applicant(s)/Patent Under  
Reexamination  
LEFEVRE ET AL.

Examiner

CHRISTINE CHEN

Art Unit

4116

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0104589 A1	08-2002	Van den Syde et al.	148/233
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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**FOREIGN PATENT DOCUMENTS**

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